

*“Advanced TEM and SEM methods applied to 3D nano- and microstructural investigations of Ni<sub>4</sub>Ti<sub>3</sub> precipitates in Ni-Ti (SMA)”. Schryvers D, Tirry W, Cao S, Diffusion and defect data : solid state data : part B : solid state phenomena **172/174**, 229 (2011). <http://doi.org/10.4028/www.scientific.net/SSP.172-174.229>*